Search Notes

_	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/017,471	TAKANO ET AL.	
	Examiner	Art Unit	
	Nashaat T. Nashed, Ph. D.	1656	

	SEARCHED				
Class	Subclass	Date	Examiner		
	,				
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	•				
Sequence search for interference of SEQ ID NO's: 17 and 19.		1/4/2006 1/19/06	NASH		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
WEST Search, enclosed.	1/17/2006	NASH	